

JAY SARKAR

Western Digital Corporation
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Citizenship United States

Education **The University of Texas at Austin** **Austin, Texas**
Ph.D. in Electrical & Computer Engineering (Solid-State Electronics) **December 2007**
Dissertation Title: *“Non-volatile Memory Devices beyond Process-scaled Planar Flash Technology”*
Awarded *“The Ben Streetman Prize for Outstanding Research in Electronic and Photonic Materials and Devices”*, 2007.
Dissertation Advisors: Prof. Sanjay K. Banerjee and Dr. Robert J. Gleixner of Intel.

Rice University **Houston, Texas**
M.S. in Applied Physics **May 2004**
Thesis Title: *“Engineering the electromagnetic environment in a nanostructure to study single-electron tunneling”*, advised by Prof. Alex J. Rimberg.
Awarded *Dean’s Fellowship*, 2001.

Indian Institute of Technology **Kharagpur, India**
B.Sc. (Honors) in Physics **June 2001**

Experience **Micron Technology** **San Jose, California**
Principal Data Scientist *October 2020 – present*
Responsible for research and development on data science and machine learning based modeling methodologies for storage and memory technologies, systems and design.

Western Digital Corporation (HGST) **San Jose, California**
Technologist, Solid-State Storage Analytics and Robustness R&D *Nov. 2014 – Sept. 2020*
Principal Engineer, SSD Reliability Science and Engineering *May 2013 – Oct. 2014*
Led with ownership for establishing and directing research and development on knowledge based system-level analytics methodologies for vertical innovation, aligned with design robustness of enterprise/data-center solid-state storage systems and devices (SSD). Developed the first known, patented and published causational physics-aligned and interpretable Machine Learning (ML) based prognostic methodologies for solid-state storage technologies. Research on interpretable supervised and unsupervised ML methodologies included definition, experimentation, characterization, interpretation and modeling of physics and design-aligned system-health predictors for enabling individually health-aware and autonomously field-adaptive system architectures under dynamic operational workload and stress spectra. Interfacing across multiple organizational teams, developed intellectual property and authored peer-reviewed publications disseminating developed generalizable methodologies across internal stake-holders and international research community. Along with guiding robust development methodologies, defined technical strategies for analytics methodologies, and mentored junior colleagues for realization of organizational goals.

Numonyx B.V. (Intel spin-off, now Micron) and Intel Corporation **San Jose, California**
Senior Research & Development Engineer *Oct. 2007 – Jun. 2010*
Researched and developed Phase Change Memory (PCM/3D Xpoint/Optane) science and technology at 90 and 45 nm lithographic geometries, towards enabling the novel non-volatile memory technology and potential novel schemes of information processing that leverage analog-resistive, in-memory and/or low-latency storage/memory architectures. Direct responsibilities included developing the core physical models of intrinsic operational evolution and large-array robustness of PCM technology, focused on fundamental device/array physics and statistics. Enabled and improved on technology capabilities by incorporating developed understanding towards optimizing the reliability/performance envelope of the technology – by application of developed physical and statistical models in array-programming microcode algorithm design and technology development. Played a key role in enabling PCM technology and first product to exceed 1 Million set/reset cycles

endurance, while exceeding orthogonal requirements on performance and retention. Authored peer-reviewed publications and intellectual property in a cross-functional, collaborative role with design and silicon research teams, helping enable the first successful implementation of PCM technology in the industry, subsequently in volume manufacturing at Micron and Intel.

Graduate Intern, Technical

*Mar. – Sep. 2007;
May – Aug. 2006 & 2005*

Designed, implemented, interpreted experiments and testing methodology towards understanding of Phase Change Memory device physics, materials science and reliability.

Qualcomm Incorporated, Qualcomm MEMS Technologies

San Jose, California

Senior Engineer, MEMS Research and Innovation Center

Jul. 2010 – Nov. 2012

Owned multiple, diverse areas of research and development on lifetime performance of novel MEMS-based reflective, power-efficient display technology with color and video capabilities. Technical areas included developing fundamental understanding on impact of environmental stressors, encapsulation and system design on technology figures of merit and lifetime. Established ab-initio characterization methodologies and models for intrinsic technology capabilities, across factors including aging, tribology and packaging design, demonstrating multiple strategies of design improvements by 2x – 10x for the glass-based technology.

The University of Texas at Austin, Microelectronics Research Center

Austin, Texas

Graduate Research Assistant and Ph.D. candidate

Aug. 2004 – Sep. 2007

Dissertation research demonstrated design, fabrication and characterization of a novel vertical, gate-all-around (3-D, GAA) inherently nanowire-scalable Flash memory transistor with protein-mediated ordering of nanocrystal quantum dot floating-gate for ultra-high density integration, excellent electrostatic control and reliable retention. Original research additionally developed fundamental physical and electrical models of device physics, materials science and associated robustness of Phase Change Memory science and technology at Intel Corporation.

Rice University

Houston, Texas

Graduate Research Assistant and M.S. candidate

Aug. 2001 – Aug. 2004

Thesis research on few-electron transport physics, based on a nanostructure designed, fabricated and characterized on a GaAs-AlGaAs heterostructure substrate with a 2-D electron system. Taught undergraduate laboratory classes and mentored undergraduate researchers.

J Nehru Center for Advanced Scientific Research

Bangalore, India

Summer Research Fellow & Rajiv Gandhi Talent Scholarship awardee

May – Aug., 1999 & 2000

Designed, implemented and optimized one of the first diskless, distributed memory Beowulf Clusters (a high-performance parallel computing platform based on commodity components and open-source software) in India to enable research based on molecular dynamics simulations.

Professional Service, Workshop Moderator, Solid-State Storage, International Reliability Physics Symposium 2021

Activities & Affiliations Emeritus Chair, Chair, Vice-Chair and Technical Program Committee Member, System Reliability Committee, International Reliability Physics Symposium (IRPS) 2018 - 2021

Workshop Moderator, on Solid-State Storage and Memory: “Resiliency in design, system-level considerations and role of usage analytics”, IRPS 2018

Invited Speaker, IEEE Santa Clara Valley Chapter, on SSD & ML methods 2018

(Senior) Member, IEEE (Elect. Devices, Computer & Comp. Intelligence Societies) 2005-present

Certification in Fundamentals of Technical Project Management, PM Training Pros 2012

Grand Awards Judge, Intel Science and Education Fair, Society for Science and the Public 2010

Peer reviewer: *IEEE Electron Device Letters, IEEE Transactions on Electron Devices, Journal of Electrochemical Society and Journal of Materials Science* 2007 – 2013

Awards & Honors

Invited Guest Lecturer, “Prognostics and System Health Management” graduate course, Center for Advanced Life Cycle Engineering (CALCE), Univ. of Maryland, College Park, 2019

Various corporate-internal awards at Western Digital, Qualcomm and Numonyx/Intel (including best paper award and first prize in hackathon), 2007-present

IEEE Senior Member Elevation, 2018

Ben Streetman Prize for Outstanding Research in Electronic and Photonic Materials and Devices 2007: The University of Texas at Austin - university-wide interdisciplinary award

Graduate Research Assistantship 2004-2007: Microelectronics Research Center, UT Austin (SRC/MARCO-FCRP); 2002-2004: Rice University (NSF)

Dean’s Fellowship 2001-2002: Rice Quantum Institute, Rice University

Rajiv Gandhi Science Talent Research Scholarship, 2000 and *Summer Research Fellowship*, 1999 & 2000: Awarded based on a nationally competitive selection and judging by JNCASR, India

Technical Reviewer of book proposals on Linux-based clustering technologies and open-source software, Addison Wesley Professional Publishing, CA 2000 - 2001

Patents

(bearing proofs of concept, at fundamental technology level)

“Method and System Involving Degradation of Non-Volatile Memory Based on Write Commands and Drive-Writes”, **J. Sarkar**, et al, filed July 2020

US patent pending “Method and System for Host-Assisted Data Recovery Assurance for Data Center Storage Device Architectures”, D. Helmick, C. Peterson, **J. Sarkar**, filed Jan. 2020

U.S. and international patents pending “Method and System for Autonomously Adaptive Solid-State Storage Health and Performance”, **J. Sarkar** and C. Peterson, filed Dec. 2018

U.S. patent 10,726,930 “Method and System for a Storage (SSD) drive-level failure and health prediction leveraging machine learning on internal parametric data”, **J. Sarkar**, C. Peterson, A. Sanayei, Y. Zhang, V. Mohan, issued July 2020

U.S. patent 13/535,772 “MEMS Device Encapsulation with Corner or Edge Seals”, W. Lee, **J. Sarkar**, J. Liu, R. Wieler, filed Jan. 2014

U.S. patent 8,036,016 “Maintenance Process to Enhance Memory Endurance”, **J. Sarkar** and Robert Gleixner, issued October 2011

Refereed Publications (peer-reviewed international conferences and journals)

“[Invited] Enabling Prognostics of Robust Design with Interpretable Machine Learning”, **Jay Sarkar**, Cory Peterson, 2019 *International Electron Devices Meeting (IEDM)* Dec. 2019.

“Operational Workload Impact on Robust Solid-State Storage Analyzed with Interpretable Machine Learning”, **Jay Sarkar**, Cory Peterson, 2019 *International Reliability Physics Symposium (IRPS)* April 2019, pp. 1-6.

“Machine-Learned Assessment and Prediction of Robust Solid-State Storage System Reliability Physics”, **Jay Sarkar**, Cory Peterson and Amir Sanayei, 2018 *International Reliability Physics Symposium (IRPS)* March 2018, pp. 3C.6-1 – 3C.6-8.

“Robust Error-Management and Impact of Throughput in Solid State Storage – Characterization and First System Reliability Model”, **Jay Sarkar**, Cory Peterson, Yao Zhang and Steve Lock, 2017 *Annual Reliability and Maintainability Symposium (RAMS)* Jan 2017, pp. 1-6.

“Reliability Characterization and Modeling of Solid State Storage”, **Jay Sarkar** and Frank Sun, 2015 *Annual Reliability and Maintainability Symposium (RAMS)*, Jan. 2015, pp. 1-6.

"Protein-Assembled Nanocrystal-Based Vertical Flash Memory Devices with Al₂O₃ Integration", F. Ferdousi, **J. Sarkar**, S. Tang, D. Shahrjerdi, T. Akyol, E. Tutuc, S.K. Banerjee, *Journal of Electronic Materials*, **38**, p. 438, 2009

"Vertical Flash memory devices with protein-assembled nanocrystal floating gate and Al₂O₃ control oxide", F. Ferdousi, **J. Sarkar**, D. Shahrjerdi, T. Akyol, J. P. Donnelly, E. Tutuc, S. K. Banerjee, *66th IEEE Device Research Conference* **2008**

"Evolution of Phase Change Memory characteristics with operating cycles: electrical characterization and physical modeling" **J. Sarkar** and Bob Gleixner, *Applied Physics Letters* **91**, p. 233506, 2007

"[Invited] Bio-nano approaches to fabricating quantum-dot floating gate flash memories", S. Banerjee, Shan Tang, **J. Sarkar**, Davood Shahrjerdi, Chang Lee, *International Conference on Solid State Devices and Materials* **2007**, Ibaraki, Japan

"Protein-mediated assembly of nanocrystal floating gate in a vertical flash cell", **J. Sarkar**, Shan Tang, Domingo Garcia, Sanjay Banerjee, *22nd IEEE Non Volatile Semiconductor Memory Workshop* **2007**, p. 34 – 35

"[Invited] Flash memory with nanoparticle floating gate", Sanjay Banerjee, Shan Tang, **J. Sarkar**, Davood Shahrjerdi, Chang Lee, *Particles* **2007**, Toronto, Canada

"[Invited] Data retention characterization of Phase-Change Memory arrays", B. Gleixner, A. Pirovano, **J. Sarkar**, F. Ottogalli, E. Tortorelli, M. Tosi and R. Bez, *Proceedings of 45th Annual IEEE International Reliability Physics Symposium* **2007**, p. 542 - 546

"Vertical flash memory with nanocrystal floating gate for ultra-dense integration and good retention", **J. Sarkar**, Sagnik Dey, Davood Shahrjerdi and Sanjay Banerjee, *Electron Device Letters*, **28**, p. 449 – 451, 2007

"Vertical flash memory with protein-mediated assembly of nanocrystal floating gate", **J. Sarkar**, Shan Tang, Davood Shahrjerdi and Sanjay Banerjee, *Applied Physics Letters*, **90**, p. 103512, 2007 – **editorially selected** for the *Virtual Journal of Nanoscale Science and Technology*, **15**, issue 11 (March 19th, 2007) and the *Virtual Journal of Biological Physics Research*, **13**, issue 6 (March 15th, 2007)

"Vertical (3-D) flash memory with SiGe nanocrystal floating gate", **J. Sarkar**, S. Dey, Y. Liu, D. Shahrjerdi, D. Q. Kelly and S. K. Banerjee, *64th IEEE Device Research Conference Digest* **2006**, p. 267 – 268

"Fabrication of Self-Assembled Ni Nanocrystal Flash Memories Using a Polymeric Template", D. Shahrjerdi, **J. Sarkar**, X. Gao, D. Q. Kelly, S. K. Banerjee, *64th IEEE Device Research Conference Digest*, p. 269 – 270, 2006

"Fabrication of Dense Ordered Arrays of Metal Dots for Flash Memory Application", D. Shahrjerdi, **J. Sarkar**, S. K. Banerjee, *Materials Research Society Spring Meeting*, 2006

"Improved performance of SiGe nanocrystal memory with VARIOT tunnel barrier", Y. Liu, S. Tang, S. Dey, D. Kelly, **J. Sarkar**, S. K. Banerjee, *IEEE Transactions on Electron Devices*, **53**, p. 2598 – 2602, 2006

"Engineering the electromagnetic environment in a semiconductor nanostructure to study single electron tunneling oscillations", **J. Sarkar**, Zhongqing Zhi, Alex Rimberg, *APS Annual March Meeting*, Montreal, **2004**

References Available on request.